## **Restep Power System**

## **Bug Report**

This document captures all of the known hardware and software problems and areas for improvement, as well as proposed methods to correct those problems.

## Hardware

1. **Problem:** The absolute maximum voltage on any microcontroller pin is Vcc + 0.5V. Pins 22, 26, 27, 40 & 41 could potentially have voltages applied to them before the microcontroller is powered.

**Solution:** Installed BAT54C diodes from microcontroller input pins to 5V. This keeps the pin voltages to < Vcc + 0.5V at all times. When the 5V comes up, the diodes will be reverse biased, and only the 7uA leakage current will influence the voltage readings.

2. **Problem:** The 48V boost converter FET failed repeatedly during testing at full load and low line. Suspect the conditions caused the FET to operate outside it's safe operating area (SOA).

**Solution:** Replaced the SQJA92EP-T1\_GE3 FET with SUM70060E. NOTE: this is not a drop-in replacement and the pad must be changed in the next PCB layout revision. Another aspect to consider is the reverse recovery of the diode. The SDT5H100P5-7 datasheet provides no reverse recovery information, and a diode with better reverse recovery may reduce power loss in the FET.

- 3. **Problem:** ICSP header pinout does not match the standard.
  - **Solution:** Change the ICSP header pinout to match the standard in the next PCB layout revision. This will simplify burning the bootloader in the microcontroller.
- 4. **Problem:** The INA230 is not recommended for new designs. **Solution:** Replace the INA230 with the INA233, which supports the same PMBus messaging and packet error checking (PEC). NOTE: this is not a drop-in replacement and the pad must be changed in the next PCB layout revision.

## <u>Software</u>

 Problem: The function UpdateLastIndex (line 519) repeatedly overwrites locations 0 and 1 in the serial EEPROM and will wear level those memory locations relatively quickly.
Solution: Re-write the function to move the index locations around the EEPROM so that there is less chance of wear leveling.

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